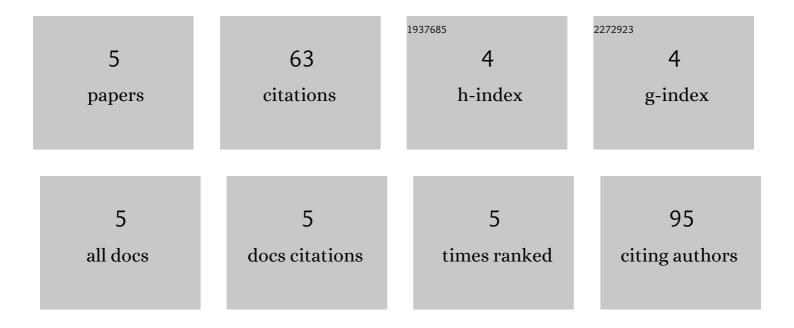
## Slah Hlali

List of Publications by Year in descending order

Source: https://exaly.com/author-pdf/9168966/publications.pdf Version: 2024-02-01



#	Article	IF	CITATIONS
1	Effect of interface traps for ultra-thin high-k gate dielectric based MIS devices on the capacitance-voltage characteristics. Microelectronics Reliability, 2017, 75, 154-161.	1.7	25
2	High temperature and voltage dependent electrical and dielectric properties of TiN/Al2O3/p-Si MIS structure. Journal of Alloys and Compounds, 2017, 713, 194-203.	5.5	19
3	High-k dielectric materials for the gate oxide of a MIS capacitor: effect of interface states on the C–V characteristics. Journal of Computational Electronics, 2016, 15, 1340-1350.	2.5	13
4	Electrical characteristics of metal–insulator–semiconductor and metal–insulator–semiconductor–insulator–metal capacitors under different high-k gate dielectrics investigated in the semi-classical and quantum mechanical models. Bulletin of Materials Science, 2017, 40, 67-78.	1.7	6
5	Charge density at the Al2O3/Si interface in Metal–Insulator–Semiconductor devices: Semiclassical and quantum mechanical descriptions. Semiconductors, 2017, 51, 1625-1633.	0.5	0